



Institute of Electrical Engineering SAS

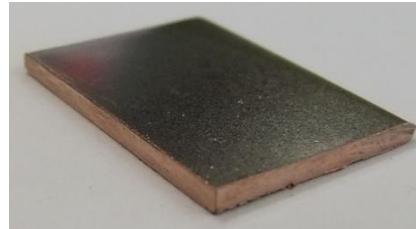
Eugen SEILER, Rastislav RIES

# **SC characterization at IEE Bratislava results, status**

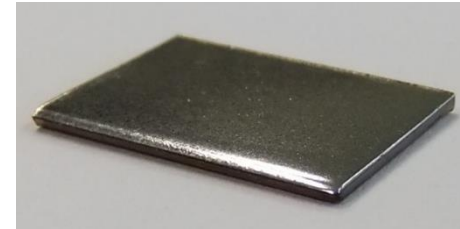
# Samples tested at IEE

**C10 ; L8 ; L16 ; L20 ; L21** – received from INFN Legnaro

**C1 ; L1 ; L10 ; L9 ; L23** – received from Uni Siegen pieces ~ 12 x 17 mm



2 edges cut @ Legnaro



2 edges covered w. Nb

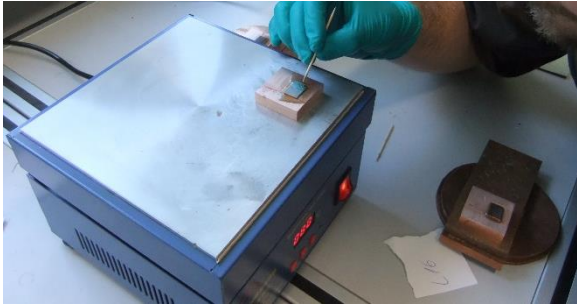
Samples for measurements (in PPMS) cut with “Diamond” saw

– circular saw, SiC cut-off disk used

– water-based cooling liquid



Master samples “glued” to Cu support blocks with Bee-wax / Colophony mixture (~ 2:1)  
**C10** and **L16** – Nb layer covered with bee-wax (thin layer) for protection @ cutting

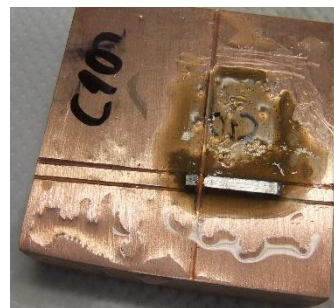


melting ~80 °C (pure bee-wax ~60 °C)

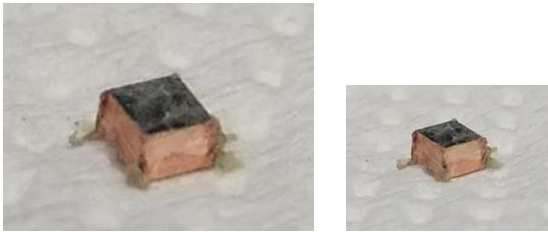


Cu blocks 5x5x1 cm

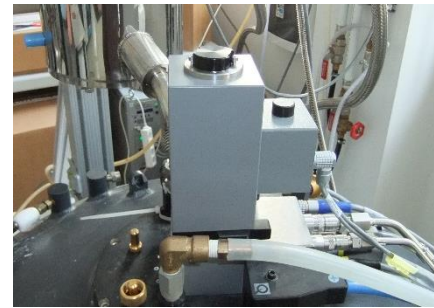
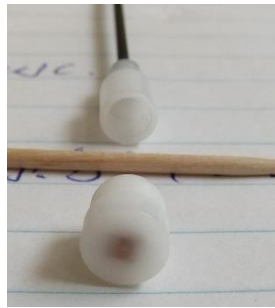
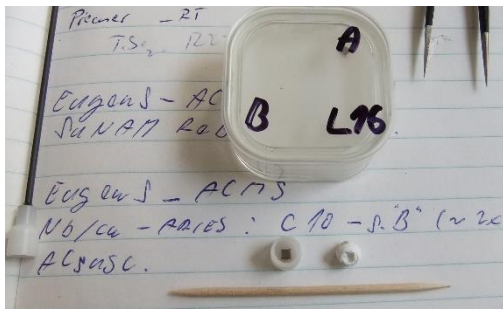
After cutting a line whole area was flushed with Ethanol, dried



Produced samples ~ 2x2 mm, OK for both AC susc. and VSM in PPMS



Mounting in sample holder of AC susceptometer (ACMS)



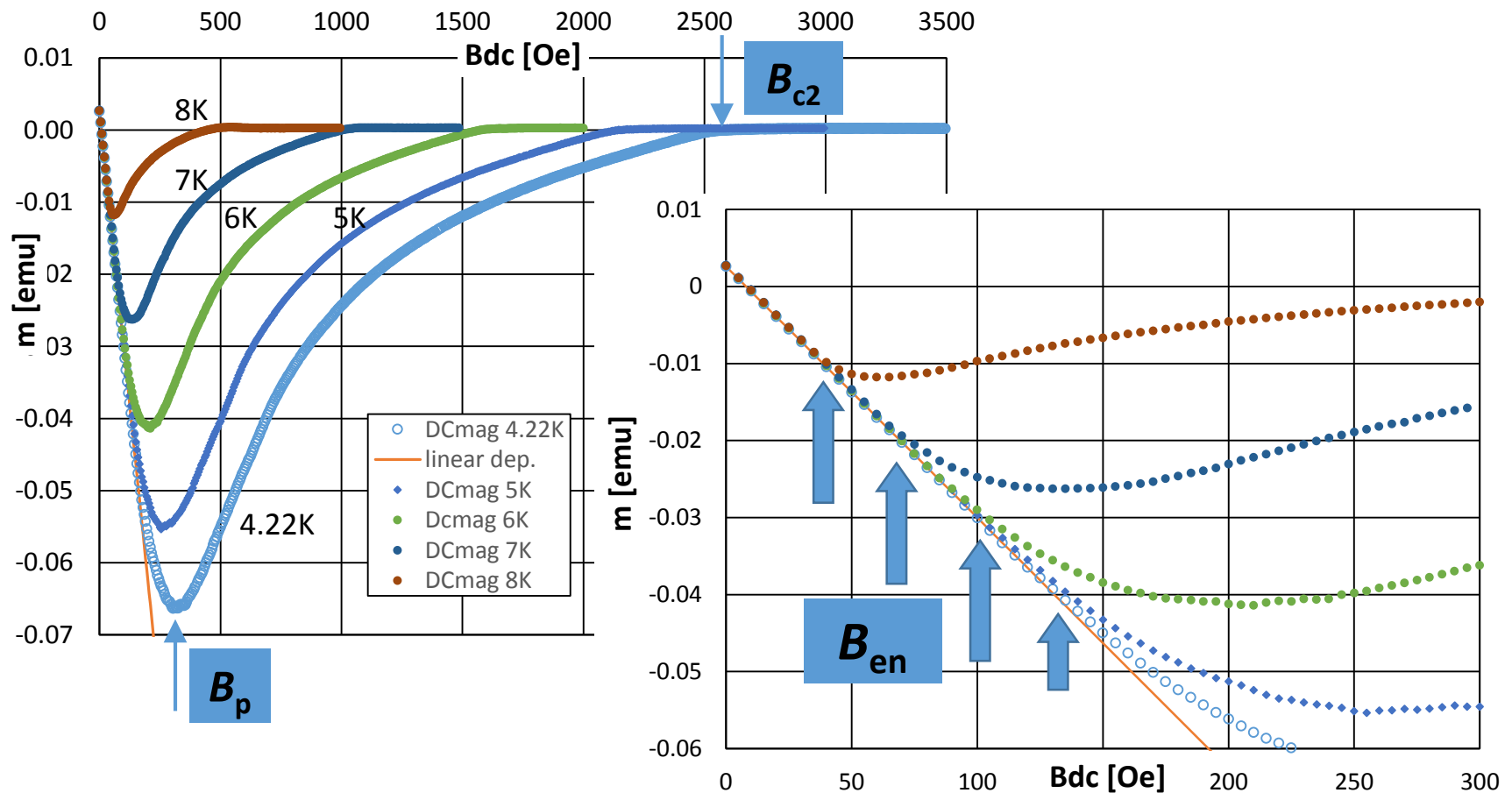
For measurements in perpendicular applied field

# SC Characterisation results

## DC magnetization

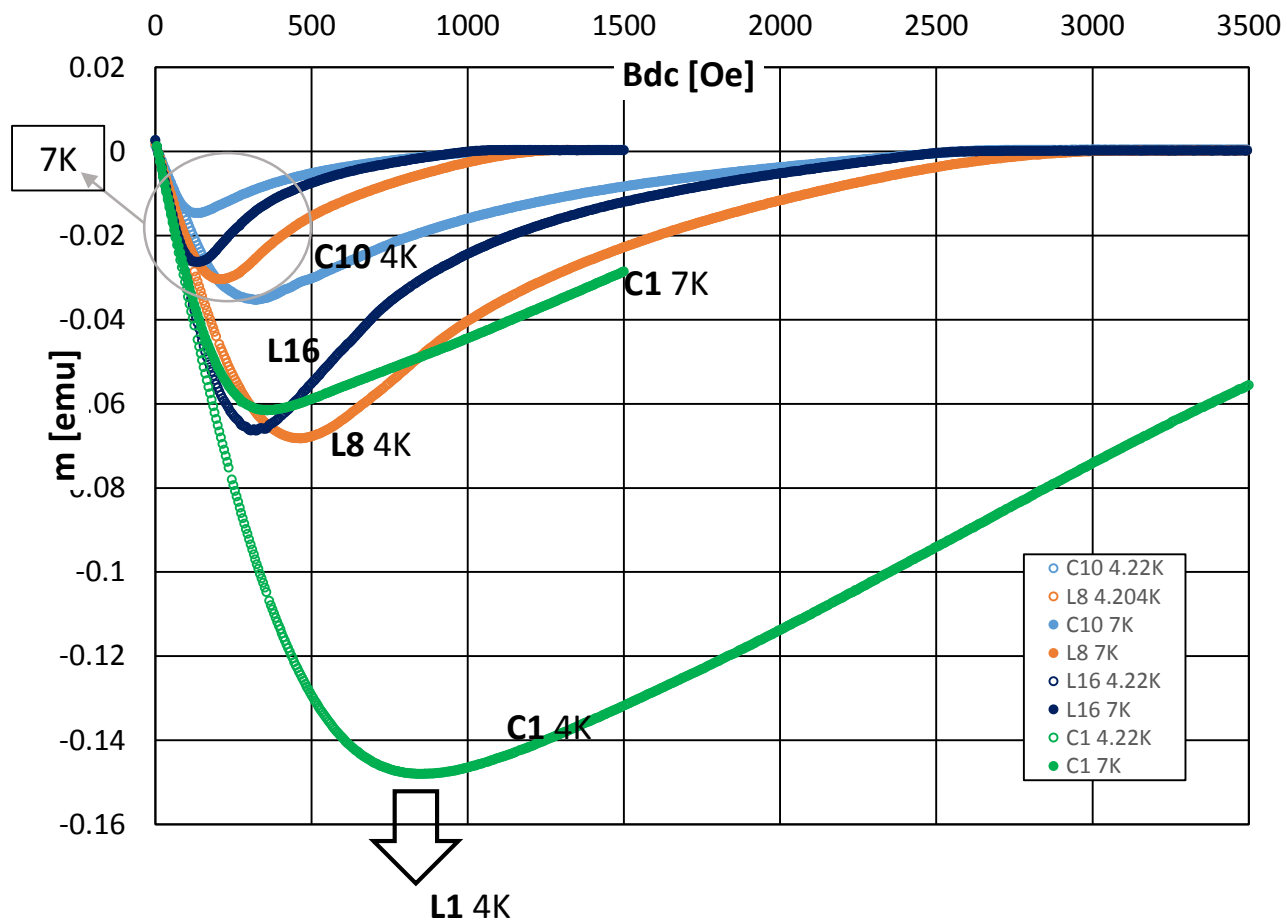
– virgin mag. curve:  $B_{en}$  ( $\sim B_{c1}$  perp.),  $[B_p, B_{c2}]$

sample **L16** (example):



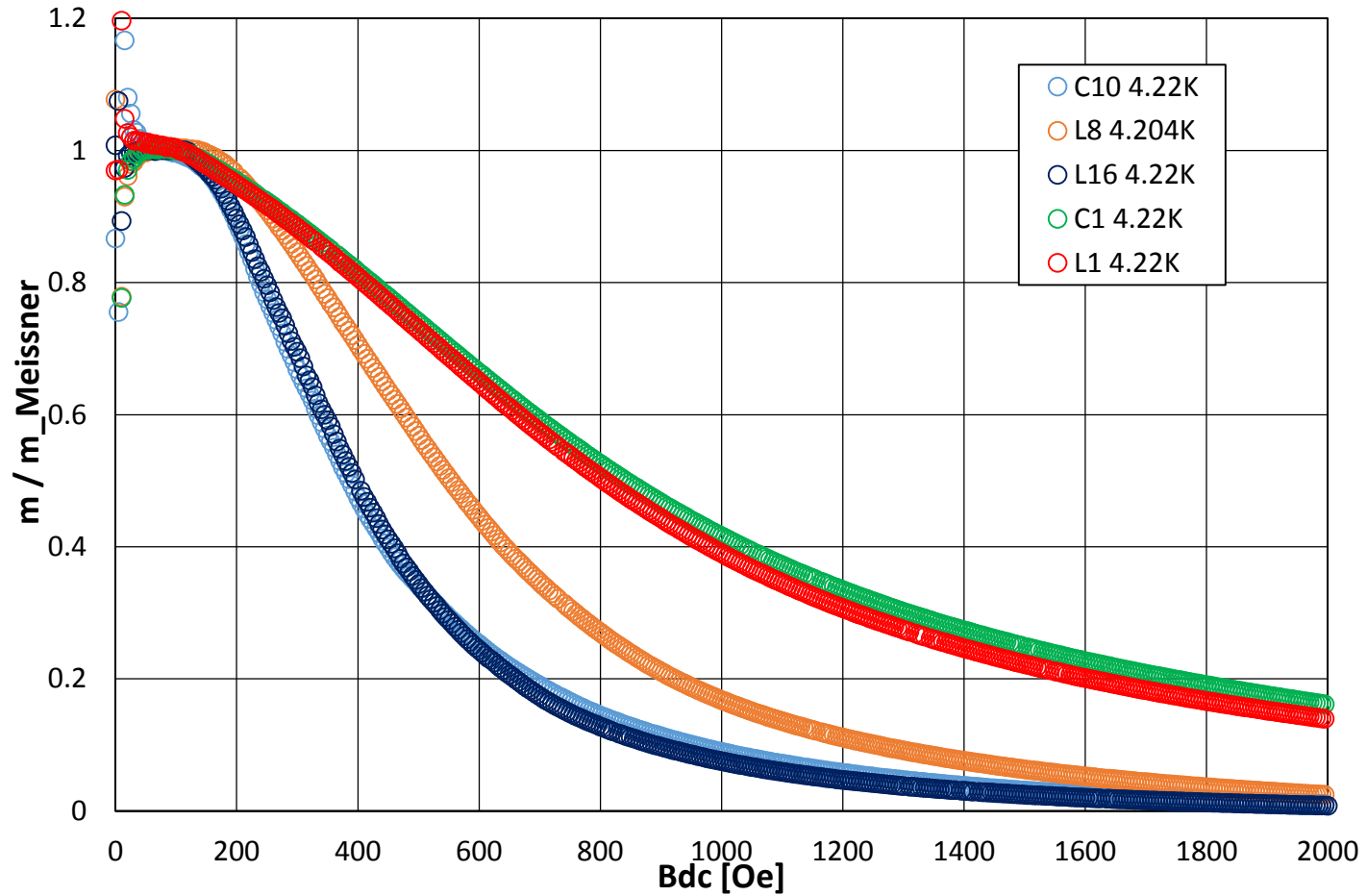
# Comparison of samples

virgin mag. curves:

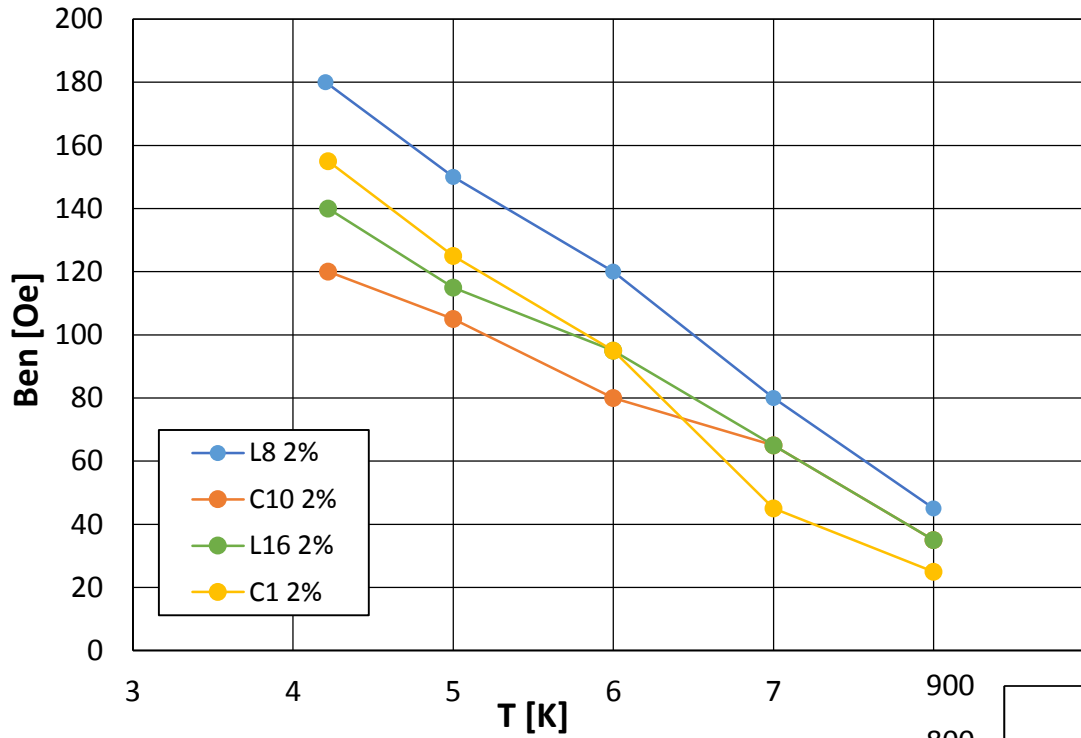


Virgin curves normalized to the linear fit of the initial (Meissner) part

$$m_{\text{Meissner}} = A * B_{dc} + B$$



Flux entry field  $B_{en}$  (proportional to  $B_{c1}$ )

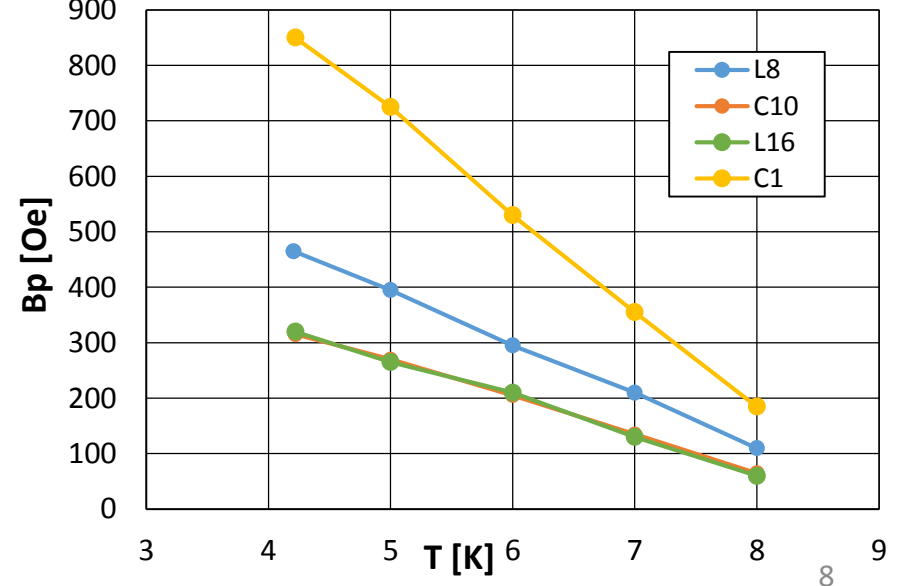


Brandt, general aspect ratio:

$$B_{en} / B_{c1} \sim \tanh(\sqrt{0.36} t/w)$$

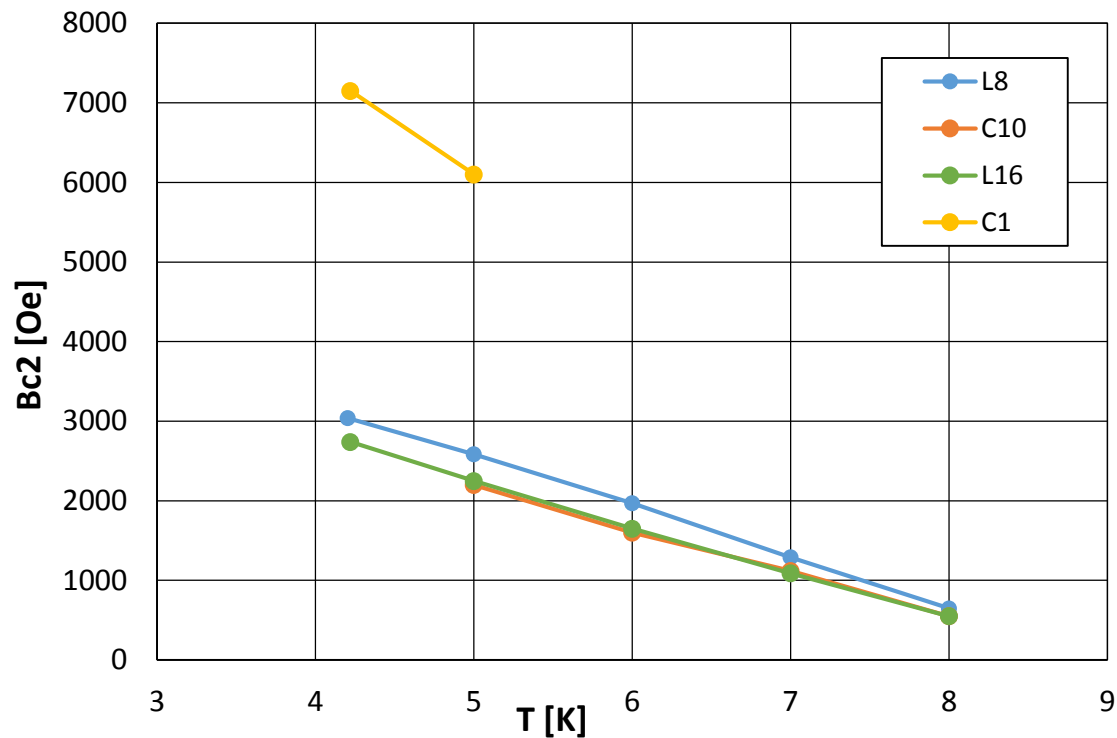
Does not work reasonably for our samples ( $B_{c1} \sim 500\text{mT}$ )

“Full penetration” field  $B_p$





## Upper critical field $B_{c2}$



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To compare the different samples more properly – **Thickness**

Do we know the Nb thickness for the samples?

# New set-up for 3<sup>rd</sup> harmonic voltage measurement – Still in preparation ...

- Small AC coil ( $\varnothing \sim \text{mm}$ ) close to big ( $\sim \text{cm}$ 's) flat sample – thin film
- $B \parallel$  surface, edge effects negligible

Sample holder prepared

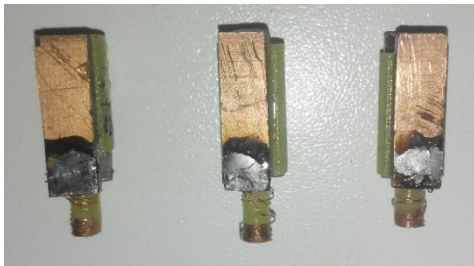
Electronic circuit tested, better amplifier necessary

“A” type amplifier acquired (17.5.)

Splitting field generation & 3f voltage detection

2 mini-coils, passive filter after amplifier

**Cu mini-coils:** inner  $d = 1.25 \text{ mm}$   
outer  $d = 3.45 \text{ mm}$   
height  $h = 2.2 \text{ mm}$   
turns  $N = 235$



***Thank you***  
***for your attention***